

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	5307	(multiplier\$1 or multiplication or multiplying) and (adder\$1 or addition or accumulat\$3) and shift\$3 and (floating-point\$1 or (floating adj. point\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 16:36
L2	2898	(multiplexor\$3 or mux or multiplex\$3) and 1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 16:40
L3	2290	normal\$5 and 2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 16:40
L4	1124	round\$3 and 3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 16:40
L5	320	((multiplier\$1 or multiplication or multiplying).ti. or (multiplier\$1 or multiplication or multiplying).clm. or (multiplier\$1 or multiplication or multiplying).ab.) and 4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 16:41
L6	217	5 and "708"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 16:41
L7	80	(shift.ti. or shift.clm. or shift.ab.) and 6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 17:02
L8	22	"4866652"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 17:02
L9	17	("4866652").URPN.	USPAT	OR	ON	2005/02/01 17:02
L10	1	("4760551").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/02/01 17:02
L11	326	708/495,501,708.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 17:50

L12	34	11 and 5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 17:50
-----	----	----------	---	----	----	------------------

[IEEE Home](#) | [Search IEEE](#) | [Shop](#) | [Web Account](#) | [Contact IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore**
DatabaseWelcome
United States Patent and Trademark
Office**IEEE Xplore**
1 Million Documents
1 Million Users[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)» [Search Results](#)**Welcome to IEEE Xplore**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Index of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Information

- ☐ Access the IEEE Information File Cabinet

[Print Format](#)Your search matched **0** of **1123491** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or entering a new one in the text box.

 ☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**Results:****No documents matched your query.**[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)

[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)
IEEE Xplore
RELEASE 1.3

 Welcome
 United States Patent and Trademark
 Office

IEEE Xplore
 1 Million Documents
 1 Million Users

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)
[Quick Links](#)

» Search Results

Welcome to IEEE Xplore

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Table of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Join IEEE

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Xplore

- ☐ Access the IEEE Xplore Full-Text

Print Format

 Your search matched **2** of **1123491** documents.

 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

 (multiplier <or> multiplication) <and> (floating point <or>
☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

1 Resolution improvement of measurement systems through optimal filtering techniques-Implementation issues on discrete signal processors

Demoment, G.; Reynaud, R.;

Instrumentation and Measurement Technology Conference, 1993. IMTC/93. Conference Record., IEEE , 18-20 May 1993

Pages:391 - 396

[\[Abstract\]](#) [\[PDF Full-Text \(572 KB\)\]](#) **IEEE CNF**

2 A VLIW architecture for logarithmic arithmetic

Arnold, M.G.;

Digital System Design, 2003. Proceedings. Euromicro Symposium on , 1-6 Sept. 2003

Pages:294 - 302

[\[Abstract\]](#) [\[PDF Full-Text \(379 KB\)\]](#) **IEEE CNF**
[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved